

INTEGRATED TYPE PROBE CARD AND ITS FABRICATION METHOD

ABSTRACT OF THE DISCLOSURE

5 An integrated type probe card includes a circuit space converter having first
and second contacts arranged at different density at two sides, probes connected to the
contacts at one side of the circuit space converter that are arranged at a high density
probes; a spring connector plate, which holds metal spring members in respective
receiving holes thereof, a circuit board pressed on the metal spring members against
10 the contacts at the other side of the circuit space converter that are arranged at a low
density, and a level adjustment mechanism that accommodates the probes, the circuit
space converter, the spring connector plate and the circuit board and enables the user to
adjust the level status of the circuit space converter, keeping the circuit space converter
electrically connected to the circuit board for transmitting test signal from the probes to
15 the circuit board.